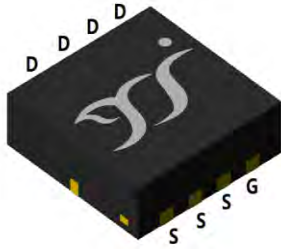
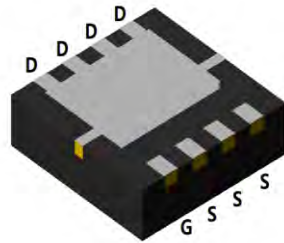


## N-Channel Enhancement Mode Field Effect Transistor

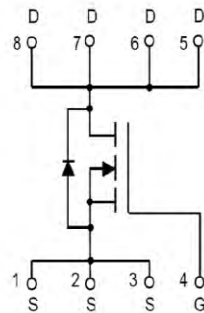


Top View



Bottom View

**DFN3333-8L**



### Product Summary

- $V_{DS}$  60V
- $I_D$  (Silicon limited) 62A
- $R_{DS(ON)}$  ( at  $V_{GS}=10V$ ) < 7.5 mohm
- $R_{DS(ON)}$  ( at  $V_{GS}=4.5V$ ) < 10 mohm
- 100% EAS Tested

### General Description

- Split Gate Trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$
- Moisture Sensitivity Level 3
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

### Applications

- DC-DC Converters
- Power management functions
- Industrial and Motor Drive application

### ■ Absolute Maximum Ratings ( $T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter		Symbol	Limit	Unit
Drain-source Voltage		$V_{DS}$	60	V
Gate-source Voltage		$V_{GS}$	$\pm 20$	V
Drain Current (Silicon limited)	$T_A=25^\circ\text{C}$	$I_D$	12	A
	$T_A=100^\circ\text{C}$		7.5	
	$T_C=25^\circ\text{C}$		62	
	$T_C=100^\circ\text{C}$		39	
Pulsed Drain Current <sup>A</sup>		$I_{DM}$	186	A
Avalanche energy <sup>B</sup>		$E_{AS}$	162	mJ
Total Power Dissipation <sup>C</sup>	$T_A=25^\circ\text{C}$	$P_D$	2.2	W
	$T_A=100^\circ\text{C}$		0.9	
	$T_C=25^\circ\text{C}$		45	
	$T_C=100^\circ\text{C}$		18	
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55 ~ +150	$^\circ\text{C}$

### ■ Thermal resistance

Parameter		Symbol	Typ	Max	Units
Thermal Resistance Junction-to-Ambient <sup>D</sup>	$t \leq 10S$	$R_{\theta JA}$	18	22	$^\circ\text{C/W}$
Thermal Resistance Junction-to-Ambient <sup>D</sup>	Steady-State		45	55	
Thermal Resistance Junction-to-Case	Steady-State	$R_{\theta JC}$	2.3	2.8	

### ■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
FTK62G06ADFN33	F1	Q62G06	5000	10000	100000	13" reel



# FTK62G06ADFN33

## ■ Electrical Characteristics (T<sub>J</sub>=25 °C unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> =250μA	60			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	T <sub>J</sub> =25 °C		1	μA
			T <sub>J</sub> =55 °C		5	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ± 20V, V <sub>DS</sub> =0V			± 100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA	1.2	1.7	2.5	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> =20A		5.8	7.5	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> =10A		7.3	10	
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =20A, V <sub>GS</sub> =0V		0.85	1.3	V
Maximum Body-Diode Continuous Current	I <sub>S</sub>				62	A
<b>Dynamic Parameters</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =35V, V <sub>GS</sub> =0V, f=1MHZ		2000		pF
Output Capacitance	C <sub>oss</sub>			390		
Reverse Transfer Capacitance	C <sub>rss</sub>			13		
Gate Resistance	R <sub>g</sub>	f=1MHZ, Open drain		1.6		Ω
<b>Switching Parameters</b>						
Total Gate Charge	Q <sub>g</sub> (10V)	V <sub>DS</sub> =30V, I <sub>D</sub> =20A		34		nC
Total Gate Charge	Q <sub>g</sub> (4.5V)			15.8		
Gate-Source Charge	Q <sub>gs</sub>			7.8		
Gate-Drain Charge	Q <sub>gd</sub>			5.2		
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> =20A, di/dt=200A/us		36		ns
Reverse Recovery Time	t <sub>rr</sub>			27		
Turn-on Delay Time	t <sub>D(on)</sub>	V <sub>GS</sub> =10V, V <sub>DD</sub> =30V, I <sub>D</sub> =12A R <sub>GEN</sub> =3Ω		10		ns
Turn-on Rise Time	t <sub>r</sub>			36		
Turn-off Delay Time	t <sub>D(off)</sub>			30		
Turn-off fall Time	t <sub>f</sub>			57		

A. Repetitive rating; pulse width limited by max. junction temperature.

B. V<sub>DD</sub>=50V, R<sub>G</sub>=25Ω, L=1mH, I<sub>AS</sub>=18A,.

C. P<sub>d</sub> is based on max. junction temperature, using junction-case thermal resistance.

D. The value of R<sub>θJA</sub> is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub> =25°C. The Power dissipation P<sub>DSM</sub> is based on R<sub>θJA</sub> t<sub>s</sub> ≤ 10s and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design.

## ■ Typical Performance Characteristics

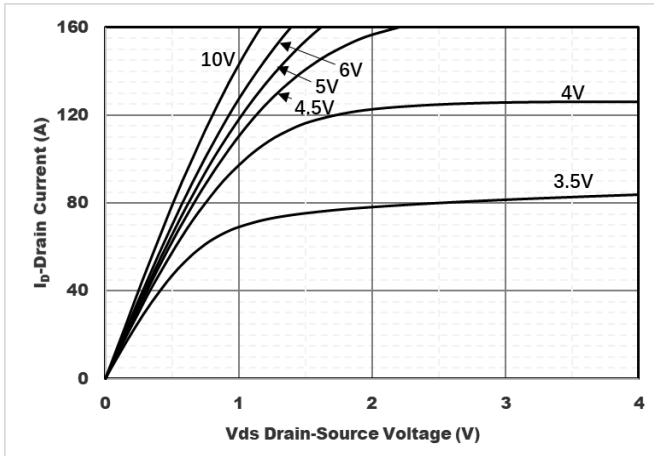


Figure1. Output Characteristics

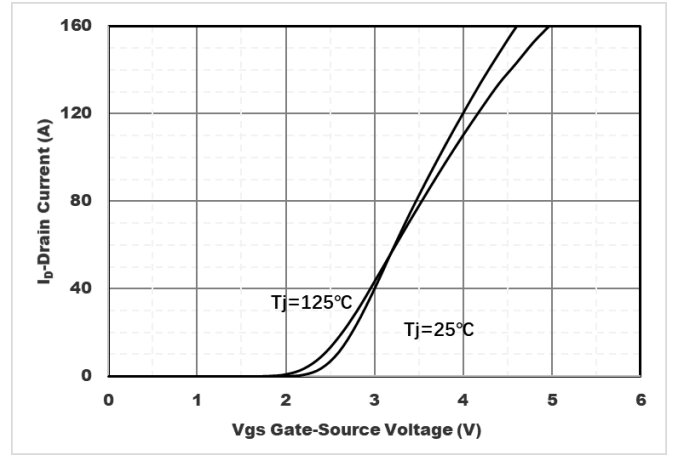


Figure2. Transfer Characteristics

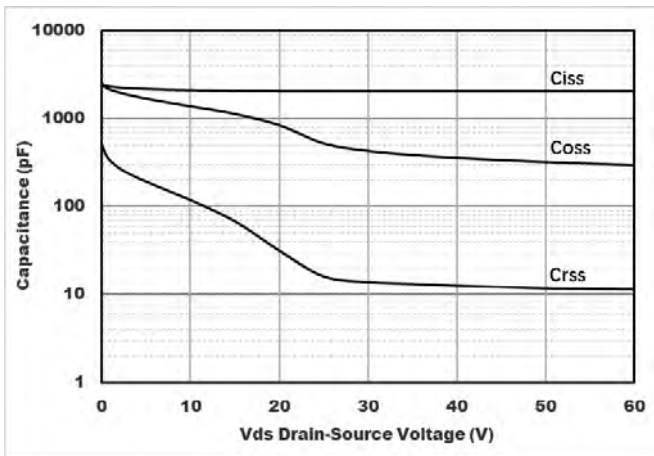


Figure3. Capacitance Characteristics

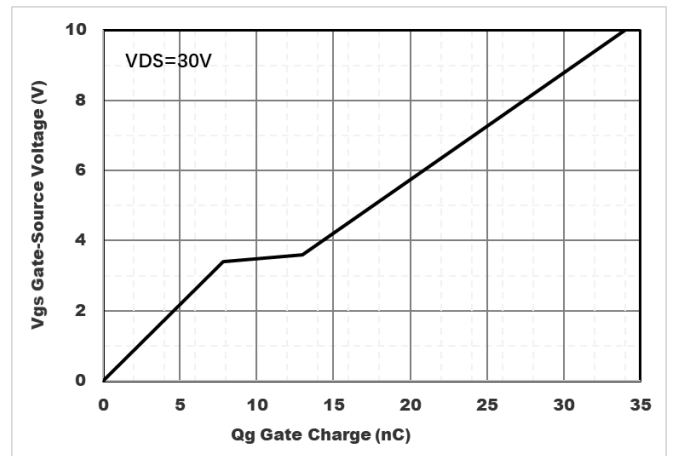


Figure4. Gate Charge

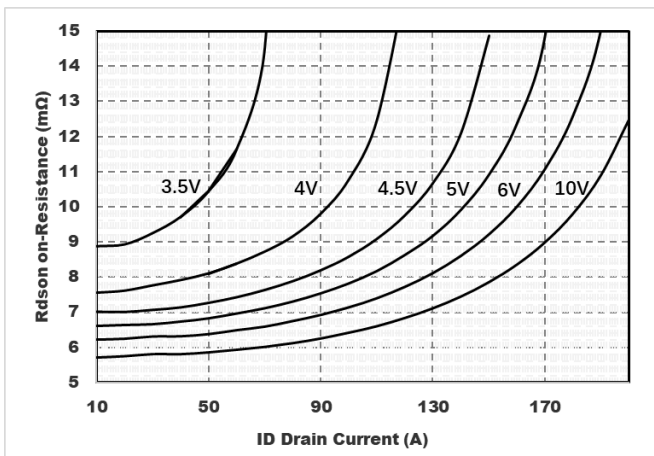


Figure5. Drain-Source on Resistance

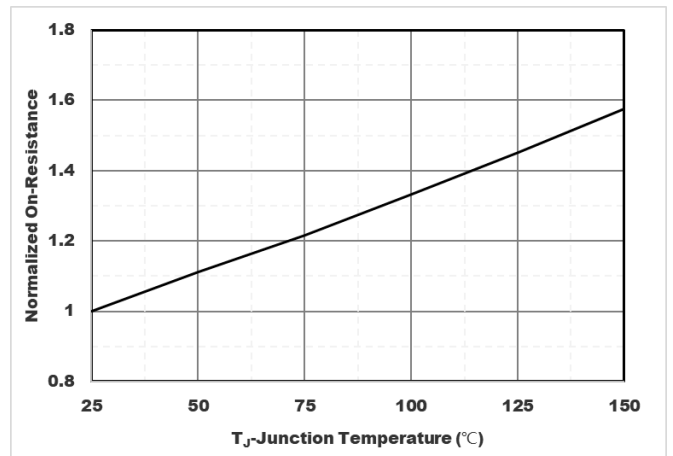


Figure6. Normalized On-Resistance

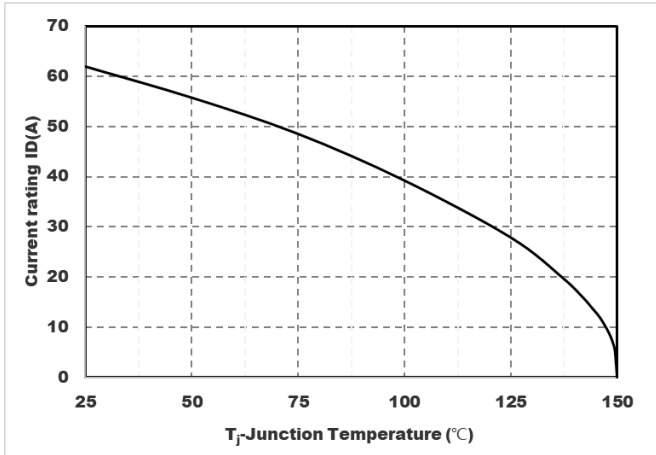


Figure7. Drain current

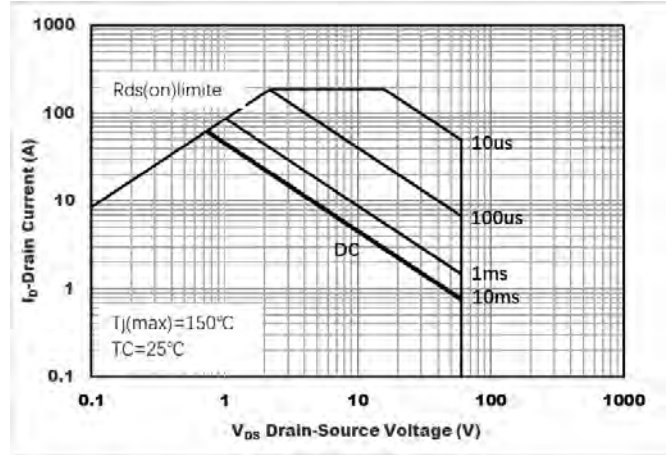


Figure8. Safe Operation Area

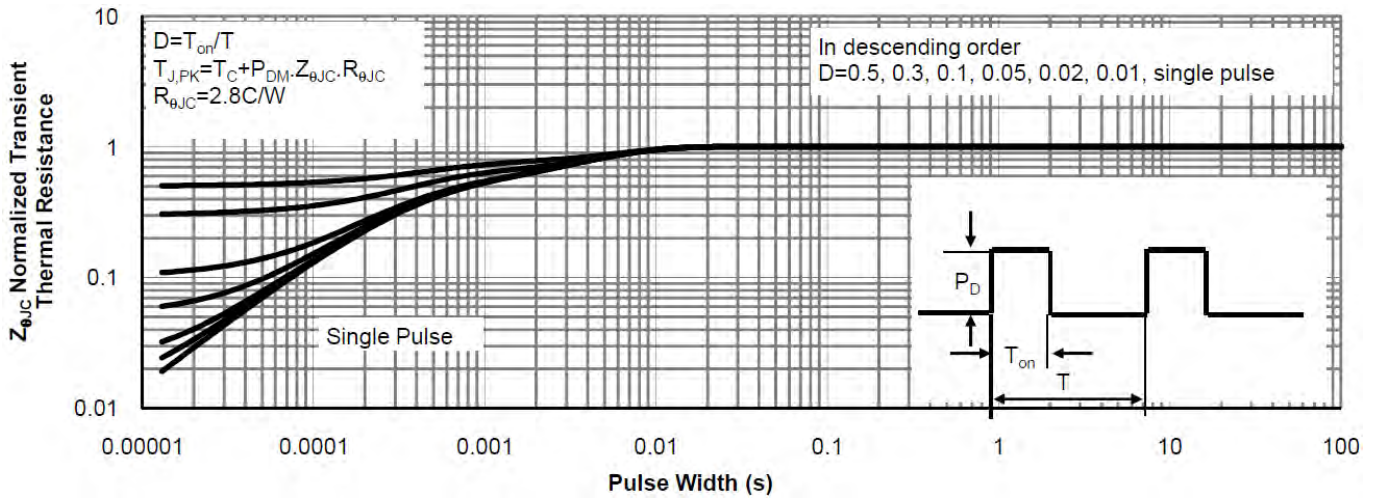
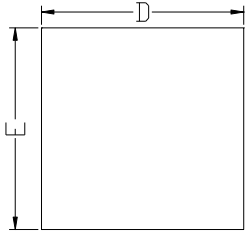
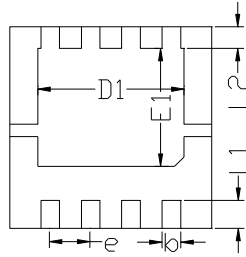


Figure8. Normalized Maximum Transient Thermal Impedance

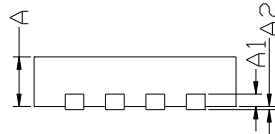
## DFN3333-8L Package information



Top View

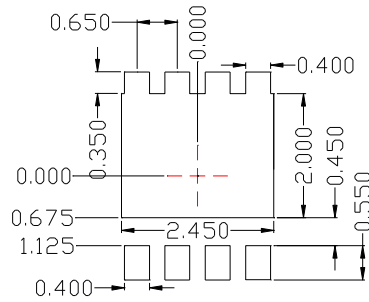


Bottom View



Side View

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	3.15	3.25	3.35
E	3.15	3.25	3.35
A	0.70	0.80	0.90
A1	0.20 BSC		
A2			0.10
D1	2.20	2.35	2.50
E1	1.80	1.90	2.00
L1	0.35	0.45	0.55
L2	0.35 BSC		
b	0.20	0.30	0.40
e	0.65 BSC		



Suggested Solder Pad Layout  
Top View

- Note:
1. Controlling dimension: in millimeters.
  2. General tolerance:  $\pm 0.10\text{mm}$ .
  3. The pad layout is for reference purposes only.